

Notice of References Cited		Application/Control No.	Applicant(s)/Patent Under Reexamination	
		10/533,893	MASUDA, TAKESHI	
		Examiner	Art Unit	Page 1 of 1
		Evan Dzierzynski	2875	

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*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-6,335,999	01-2002	Winston et al.	385/146
*	B	US-2002/0149925	10-2002	Epstein et al.	362/31
	C	US-			
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	I	US-			
	J	US-			
	K	US-			
	L	US-			
	M	US-			

FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
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NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
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